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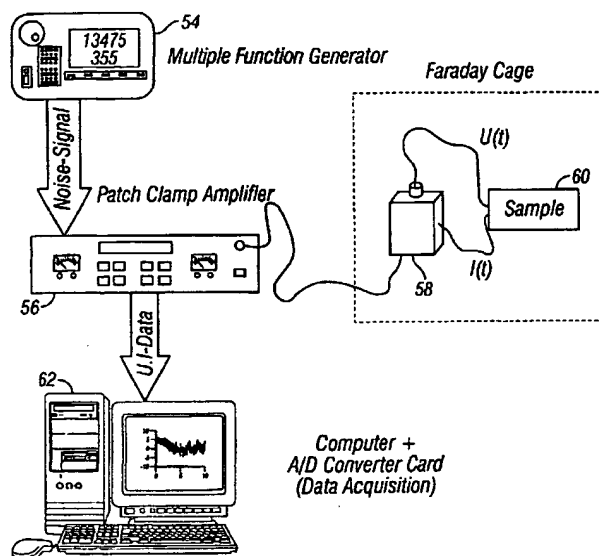
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(54) Title: METHOD AND DEVICE FOR PERFORMING IMPEDANCE SPECTROSCOPY



(57) Abstract: A highly time resolved impedance spectroscopy that enhances the measurement of the dynamics of non-stationary systems with enhanced time resolution. The highly time resolved impedance spectroscopy includes an optimized, frequency rich a.c., or transient, voltage signal is used as the perturbation signal, non-stationary time to frequency transformation algorithms are used when processing the measured time signals of the voltage and current to determine impedance spectra which are localized in time; and the system-characterizing quantities are determined from the impedance spectra using equivalent circuit fitting in a time-resolution-optimized form. Methods and apparatus for processing impedance spectra data are also provided.

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METHOD AND DEVICE FOR PERFORMING IMPEDANCE SPECTROSCOPY

5 TECHNICAL FIELD

This invention relates generally to the measurement of electrical impedance and, more particularly, to electrochemical impedance spectroscopy.

BACKGROUND ART

10 Impedance spectroscopy is a procedure used to characterize the electrical and electrochemical properties of investigated systems, and their changes over time. Typically, an a.c. voltage signal is applied between a working electrode and a counter electrode. If applicable, a simultaneously applied d.c. bias voltage is monitored with a reference electrode. Both the applied a.c. voltage signal, as well
15 as the current response of the system, are measured. The complex electrical resistance (termed the impedance $Z(\omega)$) of a system can be calculated as a function of the frequency from the quotients of the voltage and current signals in the frequency domain according to equation (1). The impedance values for a number of frequencies define the impedance spectrum.

20

$$Z(\omega) = \frac{\hat{U}(\omega)}{\hat{I}(\omega)}. \quad (1)$$

Various electrical properties of the system or electrochemical processes can be derived from the characteristics of the impedance spectra. Particularly for systems in which direct current cannot flow, a.c. or transient voltage signals must
25 be used for investigations. Due to the high information content of impedance spectroscopy, it is frequently the preferred technique for measurement of impedance spectra. For example, in electrochemistry, impedance spectroscopy is a standard analysis technique for investigating e.g. corrosion processes, redox reactions, liquid and solid electrolytes, thin polymer films, membranes and

batteries. Several papers have provided an introduction and overview of the technique and application of electrochemical impedance spectroscopy. See J.R. MacDonald: "Impedance Spectroscopy." (John Wiley & Sons, New York: 1987) and C. Gabrielli: Technical Report No. No. 004/83. 1983; C. Gabrielli: Technical Report No. part. No. 12860013. 1990.), both of which are incorporated by reference in their entirety herein.

Impedance spectroscopy is also used to characterize semiconductor materials (See A. Bard: Electrochemical Methods. (Wiley & Sons, New York: 1980)); and in biotechnology (See B.A. Cornell, Braach-Maksvytis, L.G. King *et al.*: "A Biosensor that Uses Ion-Channel Switches." Nature. 387, p.580-583 (1997). S. Gritsch, P. Nollert, F. Jähnig *et al.*: "Impedance Spectroscopy of Porin and Gramicidin Pores Reconstituted into Supported Lipid Bilayers on Indium-Tin-Oxide Electrodes." Langmuir. 14 (11), 3118-3125 (1998). C. Steinem, A. Janshoff and M. Siber: "Impedance Analysis of Ion Transport Through Gramicidin Channels Incorporated by reference in Solid Supported Lipid Bilayers." Bioelectrochemistry and Bioenergetics. 42 (2), 213 (1997)). All of the above referenced publications are incorporated by reference in their entirety herein.

The use of impedance spectroscopy has increased greatly, particularly in the field of biotechnology. In most cases, the electrodes are modified by chemical or physical coupling of biofunctional molecules and aggregates (e.g. lipid/protein membranes). Impedance spectroscopy is also used to detect adsorption processes.

There are two forms of impedance spectroscopy: Measuring impedance spectra in the frequency domain, Method I; and in the time domain, Method II.

Method I (frequency domain procedure): In the first form, a sinusoidal signal at a constant frequency and amplitude is applied within a discrete period, and the complex impedance of this discrete frequency is determined. To obtain a spectrum, sequential signals at different frequencies are applied. The time resolution, defined as the length of time in which the determined spectra follow each other, is low in this form of impedance spectroscopy. The time for acquiring the data records that compose the spectrum is a multiple of the period of the lowest frequency contained in the spectrum. The precise duration also depends on

the number of the frequencies in the spectrum. Following a frequency change, a transition period is allowed for the system to attain an equilibrium. The time resolution of a typical sequence of spectra is a few seconds to minutes depending on the observed frequency band.

- 5 Method II (time domain procedure): In the second form, a frequency rich a.c. voltage signal is applied such as square wave pulses, structured or white noise. By using Fourier transformation, the impedance spectrum can be determined from a single data record of the time course of the voltage and current signal. Therefore, the impedance spectrum is limited regarding the bandwidth and
- 10 frequency resolution by the known limitations of Fourier transformation. The measurement time is normally at least as long as one period of the lowest frequency in the spectrum of interest. Usually a measuring period of several periods of the lowest frequency in the spectrum is required to sufficiently improve the signal to noise ratio. The maximum time resolution depends on the repetition
- 15 rate at which the data records, or sets, for Fourier transformation are acquired. Because the impedance of all frequencies of the spectrum are measured simultaneously in this method, the time resolution is usually much better than that of the first method.

- Method I is normally used to characterize stationary systems or systems
- 20 exhibiting slow dynamics. Commercial devices (frequency response analyzers (FRA)), are available for these measurements. At present, method II is primarily used for measurements where the impedance spectra contain very low frequencies, for example, down to about 10^{-4} Hz, as required in corrosion studies.

- The electrical properties of non-stationary systems, which means systems
- 25 whose properties are not constant over time, cannot be measured in many cases with a sufficient time resolution by either Method I or Method II procedures of impedance spectroscopy. The time averaging effect of method I (summing for several periods of all the frequencies in the spectrum) and method II (over several periods of the lowest frequency contained in the spectrum) does not allow changes
- 30 in the system over time, which are faster than the averaging time, to be resolved by a sequence of impedance spectra. The averaging time must be greatly reduced for impedance spectrometers to measure non-stationary systems with sufficient

time resolution. A single impedance spectrum would then indicate the electrical states of the system localized in time. In addition, the individual spectra must be determined with high repetition rate to determine the time course of the system-characterizing quantities with a maximum time resolution.

5 An example of a non-stationary system that has not been able to be measured with conventional impedance spectroscopy includes lipid bilayer membranes with integrated, switching ion channels. The kinetics of many biological processes such as opening and closing ion channels in lipid bilayer membranes occurs on a time scale of a few milliseconds. These systems are
10 highly relevant in the fields of biotechnology and human physiology.

 Another example of a non-stationary system that has not been able to be measured with conventional impedance spectroscopy is metal and semiconductor interfaces with liquid and solid electrolytes with highly dynamic interface processes. In characterizing semiconductors and in the field of electrochemistry,
15 conventional impedance spectroscopy cannot be used for many dynamic processes such as the *in situ* observation of rapid etching processes or the relaxation of electrochemical systems after voltage jumps since the necessary time resolution is impossible in the required bandwidths.

 From the discussion above, it should be apparent that there is a need for a
20 impedance spectroscopy method and apparatus that can measure non-stationary systems with high dynamics. The present invention fulfills this need.

DISCLOSURE OF THE INVENTION

 A method and apparatus to measure impedance and impedance spectra in
25 rapid sequence. Measurement of impedance, and impedance spectra, in rapid sequence provides repeated or continuous characterization of the electrical properties of the system under investigation. Highly time resolved impedance spectroscopy enhances the measurement of the dynamics of non-stationary systems due to its enhanced time resolution.

30 Three aspects of highly time resolved impedance spectroscopy are: (1) an optimized, frequency rich a.c., or transient, voltage signal is used as the perturbation signal; (2) non-stationary time to frequency transformation

algorithms are used when processing the measured time signals of the voltage $U(t)$ and current $I(t)$ to determine a sequence of impedance spectra, where each spectrum is localized in time; and (3) the system-characterizing quantities are determined from the impedance spectra using equivalent circuit fitting in a time-resolution-optimized form.

The impedance data may be displayed using a color from a color scale in a two-dimensional layout that corresponds to the relative position of each channel of data within a test matrix. The arrangement of the data corresponds to the electrical readout at each electrode within the test matrix. In addition, different colors can be used for different types of data.

BRIEF DESCRIPTION OF THE DRAWINGS

Figure 1 is a plot versus time of an example of a structured noise voltage signal $U(t)$.

Figure 2 is a power spectrum density plot of structured noise voltage and current signals $U(f)$ and $I(f)$.

Figure 3 is a plot illustrating examples of a sequence of impedance spectra as a function of the frequency f and the time τ for a non-stationary system.

Figure 4 is a schematic of an equivalent circuit.

Figure 5 is a block diagram representation of one embodiment of a highly time resolved impedance spectroscopy system.

Figure 6 is a table that shows examples of parameters for the structured noise signal and data processing for the described simulations in the "Simulations" column, and for the described measurements in the "fast model" and "Gigaohm model" columns.

Figure 7 is a graph illustrating an example of the time course of the resistance R_2 of the non-stationary system of Figure 4 (simulation).

Figure 8 is a graph of an expanded portion of Figure 7 illustrating a transition in the value of R_2 .

Figure 9 is a graph illustrating an example the time course of the values of the equivalent circuit elements of Figure 4 measured with highly time resolved impedance spectroscopy.

Figure 10 (a) is a graph illustrating an example of the real part of the underlying impedance spectra for two points in the time courses in Figure 9.

Figure 10 (b) is a graph illustrating an example of the imaginary part of the underlying impedance spectra for two points in the time courses in Figure 9.

Figure 11 is a graph illustrating an example of the time course of the values of the equivalent circuit elements of Figure 4, measured with highly time resolved impedance spectroscopy.

Figure 12 (a) is a graph illustrating an example of the real part of the underlying impedance spectrum for one point in the time courses in Figure 11.

Figure 12 (b) is a graph illustrating an example of the imaginary part of the underlying impedance spectrum for one point in the time courses in Figure 11.

Figure 13 is a block diagram illustrating one embodiment of the highly time resolved impedance spectroscopy.

Figure 14 is a diagram illustrating impedance data represented as a graphical user interface (GUI).

20 BEST MODE FOR CARRYING OUT THE INVENTION

A method and apparatus to measure impedance and impedance spectra in rapid sequence thereby providing repeated or continuous characterization of the electrical properties of the system under investigation. Highly time resolved impedance spectroscopy is able to measure the dynamics of non-stationary systems with enhanced time resolution.

Three aspects of highly time resolved impedance spectroscopy are: (1) an optimized, frequency rich a.c., or transient, voltage signal is used as the perturbation signal; (2) non-stationary time to frequency transformation algorithms are used when processing the measured time signals of the voltage $U(t)$ and current $I(t)$ to determine a sequence of impedance spectra, where each spectrum is localized in time; and (3) the system-characterizing quantities are

determined from the impedance spectra using equivalent circuit fitting in a time-resolution-optimized form.

U.S. PCT patent application number U.S. 00/26765 by Weigand et.al., describes aspects of highly time resolved impedance spectroscopy; U. S. patent application number 09/353,554 by Wagner et. al., describes aspects of microdevices for screening biomolecules; and U.S. patent number 6,228,326 by Boxer et. al., describes aspects of lipid bilayer array technology, all of which are incorporated by reference in their entirety herein.

Optimized Frequency Rich Perturbation Signal

The optimized frequency rich perturbation signal may be of many different formats. A frequency rich perturbation signal may contain any desired amount of contributing frequencies which are superimposed in one signal. For example, a frequency rich perturbation signal may be the superposition of a specific number of sinusoidal oscillations, or voltage jumps, pulses, and noise signals. The higher the signal to noise ratio of the voltage perturbation and the current response signal, the lower the time expansion of the database that is required to attain a certain measuring precision.

Structured noise may be used as the perturbation signal for highly time resolved impedance spectroscopy. Structured noise is defined as the superposition of a finite number of sinusoidal oscillations. Figure 1 is a plot versus time of an example of a structured noise voltage signal $U(t)$ (18). Figure 2 is a power spectrum density plot of a structured noise voltage and current signals $U(f)$ (20) and $I(f)$ (22). The structured noise illustrated in Figures 1 and 2, can be represented mathematically by equation (2):

$$U(t) = \sum_{i=1}^n U_{0,i} \cdot \sin(\omega_i t + \phi_i) \quad \text{with } 5 \leq n \leq 50 \quad (2)$$

In equation (2), $U_{0,i}$ is the amplitude of the i -th sinusoidal oscillation with angular frequency ω_i and ϕ_i is the phase. A favorable signal to noise ratio may be obtained when the perturbation signal $U(t)$ is tuned, or optimized, to the system

and the focus of measurement. Optimization of perturbation signals has been the subject of some research. See G.S. Popkirov and R.N. Schindler: "A New Impedance Spectrometer for the Investigation of Electrochemical Systems." Rev. Sci. Instrum. 63 (11), 5366-5372 (1992).; G.S. Popkirov and R.N. Schindler: "Optimization of the Perturbation Signal for Electrochemical Impedance Spectroscopy in the Time Domain." Rev. Sci. Instrum. 64 (11), 3111-3115 (1993). All the above publications are incorporated by reference in their entirety herein.

Numerous optimization steps are an aspect of highly time resolved impedance spectroscopy including: the frequency band in which the impedance is measured; the number and frequency, amplitude and phase of the individual contributing frequencies.

Optimization of the perturbation signal includes selection of the frequency band in which the impedance spectrum is measured. Therefore, the frequency band of the perturbation signal should be selected to include the maximum spectral range to be covered by the measurement. However, when evaluating the impedance spectra one can use just selected frequencies of the n frequencies in the perturbation signal. This aspect is discussed further below.

Optimization of the perturbation signal may also include selecting a desired number (n) and frequency position (ω_i) of the n individual contributing frequencies. Any desired number and frequency positions of the individual frequencies can be used. This maximizes for the user the adaptability of the high time resolution impedance spectrometer to the system under investigation.

In one embodiment, the power applied by a structured noise signal to the sample depends on the number of the frequencies in the noise signal. Because many systems exhibit linear behavior only with small amplitude or low power perturbation, it is desirable to keep the number of frequencies as low as possible. On the other hand, the reproduction of the characteristic system response requires a minimum number of frequencies in the impedance spectrum. Because in impedance spectroscopy the impedance is usually determined over several orders of magnitude of the frequency, a desired number of individual frequencies per frequency decade is selected, if special system requirements do not require

deviating from this desired number. In one embodiment, five individual frequencies per frequency decade is a suitable number.

In one embodiment, the distribution of the frequency position of the individual frequencies is selected in a logarithmic uniform distribution over the entire frequency band. In another embodiment, the distribution of the frequency position of the individual frequencies selected is varied from a logarithmic uniform distribution in a manner to avoid the formation of harmonics. Preventing harmonics helps to prevent the corruption of the measured impedance spectra by nonlinear system responses or the excitation of higher harmonics.

Another aspect of the perturbation signal that may be optimized is the amplitude $U_{0,i}$ of the individual frequencies. Any desired amplitude of the individual frequencies may be selected. In one embodiment, to optimally exploit the linear range of a measuring amplifier, and attain an optimum signal to noise ratio for each frequency in the system, the amplitudes of the individual frequencies are adapted to the measuring situation. In one embodiment the amplitudes of the individual frequencies in the perturbation signal are such that the power of the individual frequencies in the perturbation signal is constant (good for use with strongly nonlinear systems). In another embodiment the power of the current response of the excited individual frequencies is constant (reduction of the influence of non-linearity of the measuring amplifier, see Figure. 2). In yet another embodiment, the power of the individual frequencies of the perturbation signal and the current response reveals minimal differences (optimum signal to noise ratio).

Yet another aspect of the perturbation that may be optimized is the phase ϕ_i of the individual frequencies. Any desired phase angle of the individual frequencies may be selected. In one embodiment, a linear system response may be ensured by the lowest possible overall amplitude of the perturbation signal. The phases of the individual frequencies in the structured noise are selected so that the overall amplitude of the signal is minimal while the amplitudes of the individual frequencies remain the same. Hence the power of the individual frequencies is retained despite reduced overall amplitude, or the power of the individual

frequencies is maximized and the signal to noise ratio is improved, as the overall amplitude remains fixed.

Non-Stationary Time to Frequency Transformation Algorithms

5 An aspect of highly time resolved impedance spectroscopy is the determination of impedance spectra, which are localized in time, with reduced averaging time in high repetition rate. Non-stationary time to frequency transformation algorithms are used in highly time resolved impedance spectroscopy. The averaging time corresponds to the prolongation of the database
10 that is required for determining an individual impedance spectrum. Sequences of spectra $X(\omega)$, which are localized in time, are determined from the time signals $X(t)$ by applying window functions spanning a small period of time of the measuring signal $X(t)$ (either $U(t)$ or $I(t)$) and repeating this procedure, applying window functions shifted by brief, or short, intervals. The time signals, including
15 the a.c. voltage signal $U(t)$ applied to the sample and the current response $I(t)$ of the sample, are continuously or partly continuously recorded over a given period only limited by the storage capacity of the used data storage media. A partly continuously recorded data set may be defined as a repeated recording of finite data sets of any length with arbitrary, or selected, interruption intervals between
20 consecutive data sets.

Examples of non-stationary, time to frequency transformation procedures include sliding short time Fourier transform, wavelet transformation and Wigner or Wigner-Ville distribution. Two of these methods will be described further below: (1) sliding short time Fourier transform; and (2) wavelet transformation.

25 In sliding short time Fourier transform the time to frequency transformation is carried out corresponding to the formula for continuous short time Fourier transform:

$$\hat{X}(\tau, \omega) = \int x(t) g^*(t - \tau) \cdot e^{-i\omega t} dt \quad (3)$$

In equation (3) $x(t)$ corresponds to the measured time signal, $g(t)$ is a window function whose characteristic is adjusted to optimize the spectrum $X(\tau, \omega)$ that is obtained as a result of the transformation step. See L. Cohen: Time-frequency Analysis (Prentice Hall PTR, Englewood Cliffs, NJ, 1995) incorporated by reference in its entirety herein. Various possible window functions have been described. See F.J. Harris: "On the Use of Windows for Harmonic Analysis with the Discrete Fourier Transform." Proceedings of the IEEE 66 (1), 51-83 (1978) incorporated by reference in its entirety herein.

The resulting impedance spectrum $Z(\tau, \omega)$ is obtained according to equation (1) from the quotients of the spectra of the voltage signal $U(\tau, \omega)$ and the current signal $I(\tau, \omega)$. This impedance spectrum is assigned to the time τ , that is, it characterizes the investigated sample at time τ of the measurement. The spectral information is hence localized at time τ by considering, and weighting, only a section of the overall data record around time τ for the time to frequency transformation. The impedance spectrum yields the complex impedance depending on the angular frequency $\omega = 2\pi f$ where f is the frequency. A sequence of impedance spectra is obtained by repeatedly calculating impedance spectra according to the described procedure where the time τ shifts by interval $\Delta\tau$ for each of the subsequent spectra.

Figure 3 is a plot illustrating examples of a sequence of the real (32) and imaginary (34) impedance spectra as a function of the frequency f and the time τ for a non-stationary system. In the manner described above, the measured data records are completely analyzed when τ is shifted as much as possible by interval $\Delta\tau$ in the data record from the start of measurement. If the interval $\Delta\tau$ is smaller than the prolongation of the window function $g(t)$, one speaks of sliding short time Fourier transform since the window functions $g(t-\tau)$ applied to the data records overlap within the sequence. The interval $\Delta\tau$ in which the window function shifts between each transformation, defines the time resolution of the procedure.

To attain a high time resolution, $\Delta\tau$ must be correspondingly small. Likewise, the time over which $g(t)$ is not zero must be as small as possible to reduce the time averaging in the time to frequency transformation. The window

function $g(t)$ defines the maximum peak-to-peak resolution Δt_{pp} of short time Fourier transform provided by the expression:

$$\Delta t_{pp}^2 = \frac{\int t^2 |g(t)|^2 dt}{\int |g(t)|^2 dt} \quad (4)$$

5 When the measured data records of $U(t)$ and $I(t)$ exist in discrete form, for example, in the case of computer-supported, or digitized, data acquisition, the discrete algorithm of the short time Fourier transform of equation (5) is used instead of continuous short time Fourier transform.

$$\hat{X}_a(\tau, \omega) = \sum_{n=0}^{N-1} x(nT_a) g^*(nT_a - \tau) \cdot e^{-i\omega nT_a} \quad (5)$$

10 T_a is the sampling interval for data acquisition, n the running variable for the number of observed data points, and N the total number of data points. All other quantities correspond to the definition in continuous short time Fourier transform. The shift interval $\Delta\tau$ typically is a whole-number multiple of T_a . The frequency resolution Δf and the upper frequency limit f_{\max} in each impedance spectrum are subject to the sampling theorem expressed in equation (6). See E. Schröder: Signalverarbeitung. (Hanser, Munich: 1990), incorporated by reference in its entirety herein.

$$\Delta f = \frac{1}{N_w \cdot T_a} \quad \text{and} \quad f_{\max} = \frac{1}{2 \cdot T_a} \quad (6)$$

20 where N_w is the number of data points above which the window function $g(nT_a)$ is not zero.

In wavelet transformation the time to frequency transformation is carried out corresponding to the formula of continuous wavelet transformation:

$$\tilde{X}(\tau, s) = \frac{1}{\sqrt{|s|}} \int x(t) \cdot h^* \left(\frac{t - \tau}{s} \right) dt. \quad (7)$$

See O. Rioul and M. Vetterli: "Wavelet and Signal Processing" in Signal Processing Technology and Applications. Edited by J.G. Ackenhusen (The Institute of Electrical and Electronics Engineers, Inc., New York: 1995) p.85-109
 5 incorporated by reference in its entirety herein.

Instead of the variable of the angular frequency ω , the scale s is normally used for wavelet transformation. This is due to the fact that the pulse responses of the used wavelet functions $h_s(t)$ scales with s as e.g. is the case with a basic or prototype wavelet of the formula:

10

$$h_s(t) = \frac{1}{\sqrt{|s|}} h\left(\frac{t}{s}\right) \quad (8)$$

One possible form for the window function $h(t)$ is a modulated window function $g(t)$ as is used in short time Fourier transform:

$$h(t) = g(t) e^{-i\omega_0 t}. \quad (9)$$

15

In equation (9), ω_0 corresponds to the modulation frequency of the basic, or prototype, wavelet. By scaling the basic function for the time to frequency transformation, the time resolution is not set for the entire spectrum but varies with the analyzed frequency or scale. This has an advantage that the time averaging is reduced by the time to frequency transformation at high frequencies
 20 by reducing the database. This increases the time localization and permits a substantially higher time resolution at this range. In addition, the considered database at low frequencies is expanded so that the contribution of these frequencies can be integrated into the spectral information. Overall, the
 25 information content of the determined sequence of impedance spectra may be greatly increased. The time resolution can be optimally adjusted by selecting the

suitable shift interval $\Delta\tau$ for a sequence of impedance spectra obtained by wavelet transformation, for either the entire frequency bandwidth or just selected frequencies of interest.

In the case of discrete data records, a corresponding algorithm is used for
5 discrete wavelet transformation or wavelet series expansion.

The highly time resolved impedance spectroscopy offers many advantages over conventional impedance spectroscopy including the use of reduced impedance spectra. The impedance spectra obtained by short time Fourier transformation, e.g. intrinsically includes $N_w/2 + 1$ frequencies which can be
10 reduced to the n frequencies that are contributing to the structured noise. Because the discrete algorithms only provide impedance values for discrete equidistant frequencies, frequencies are selected that are closest to the excited frequencies. This step eliminates most of the background noise of the measurement from the impedance spectra. Only the frequencies with the best signal to noise ratio are
15 contributing to the impedance spectra, allowing the use of window functions which span a smaller period of time, resulting in a lower averaging time for the spectral information.

Equivalent Circuit Fitting in a Time-Resolution-Optimized Form

20 After determining the reduced impedance spectra, the spectra may be analyzed by adapting suitable equivalent circuit models to determine the system-characteristic quantities and their time course. The elements that compose the equivalent circuits are derived from physical models for the dominant processes occurring in the system and frequently correspond to the behavior of ideal
25 electrical components such as resistors, capacitors and inductors. In the impedance spectrum, distinct processes dominate the impedance response of the system in different ranges of frequencies. In highly time resolved impedance spectroscopy, either the measured and reduced impedance spectra are evaluated completely or in certain ranges of the spectra. In principle, you can determine
30 whether or not each frequency contributing to the reduced impedance spectrum is used for evaluation.

An advantage of highly time resolved impedance spectroscopy is the possibility of multiple analyses of the same data records with different analysis parameters, e.g. time resolutions $\Delta\tau$. For the multiple analyses of data records, first impedance spectra are determined with a longer window function leading to a long averaging time and a low time resolution, and therefore the reduced impedance spectra can be evaluated completely. The parameters of the stationary, i.e., constant processes are hence determined with a high degree of precision.

The impedance spectra with a shorter window function, leading to a short averaging time and high time resolution, are determined in another analyses of the same data records. When the spectra are evaluated, only the areas of reduced spectra are used that characterize the dynamic non-stationary processes, and the parameters for the static or stationary processes in the equivalent circuit are set to the previously-determined values.

The complex impedance values can be represented in different forms. For example, the impedance can be represented by complex coordinates or polar coordinates:

$$Z(\omega) = \text{Re}[Z(\omega)] + i \cdot \text{Im}[Z(\omega)] = Z_0(\omega) \cdot e^{i\varphi(\omega)}. \quad (10)$$

Likewise, the reciprocal impedance (termed admittance) or related quantities can be used such as the complex frequency-dependant dielectric constant in both coordinate forms. The significance of individual processes in certain frequency ranges of the impedance spectra varies with the coordinate form used. For analysis, highly time resolved impedance spectroscopy may use the electrical variables and coordinate form that significantly resolve the non-stationary processes in the highest frequency range. The higher the frequencies at which the investigated processes can be analyzed allows for the selection of a smaller time period spanned by the window functions and a smaller shift interval $\Delta\tau$ for use in the sliding short time Fourier transform.

For example, a method for adapting the parameters of the equivalent circuit to the measured impedance spectra includes complex non linear least

square fitting methods. A problem of the minimization algorithm for adapting the equivalent circuit to the impedance data (e.g. Levenberg-Marquardt, Powell's minimization method in multidimensions) is that the algorithm frequently finds local minimums instead of the global minimum in the fitting. See W.H. Press, S.A. Teukolsky, W.T. Vetterling *et al.* Numerical Recipes in C (Cambridge University Press, New York, 1992) incorporated by reference in its entirety herein.

To increase the probability of determining the global minimum in the fitting, different coordinate forms and variables can be combined. In highly time resolved impedance spectroscopy, sequences of impedance spectra may be evaluated by an automatic fitting routine or process. As a result, the time courses of the system-characterizing quantities are determined.

The procedure described above is not limited to electrical impedance and can be used to determine mechanical impedance spectra such as in rheological measuring methods, magnetic and optical tweezers, quartz resonance balances and acoustic impedance measurements as well as other procedures in which the frequency rich perturbation of a system is related to the system response.

Exemplary Embodiment

One embodiment will be described in detail to assist in understanding various aspects of highly time resolved impedance spectroscopy. Although one embodiment is described in detail, highly time resolved impedance spectroscopy may be embodied in other specific forms without departing from its spirit or essential characteristics. The embodiment describes a scenario that would facilitate the measurement, or determination, of the impedance of individual ion channels in supported lipid membranes, biomembranes. In another embodiment, the impedance of natural or artificial, freely-suspended or substrated supported lipid membranes with or without ion channels may be measured. The substrates bear planar thin-film microelectrodes that are in multiple electrode arrangements, facilitating parallel and sequential multiplex measurements on the substrate. The substrates can be fabricated from, for example, silicon substrates with metal or semiconductor electrodes. The substrates may be mounted in an electrochemical

cell, of either one or multiple measuring chambers, in which liquid can be exchanged by a manual, or automated, liquid handling and control system with or without temperature control. Such a scenario corresponds to the measurement of an electrical two-terminal network that is simplified by the circuit depicted in
5 Figure. 4.

Figure 4 is a schematic of a typical equivalent circuit. The typical equivalent circuit of figure 4 has a resistor R_1 (42) in series with the paralleled combination of resistor R_{2a} (44), R_{2b} (46) and C (48). A switch is in series with R_{2a} (44). The excitation voltage $U(t)$ (50) is measured across the equivalent
10 circuit, and the response current $I(t)$ (52) flowing through the circuit is measured. Typical values of the components can be assumed to range from $R_1 \sim 100 \text{ k}\Omega$, $R_{2a, 2b} \sim 1 \text{ G}\Omega$ and $C \sim 6 \text{ pF}$. Switching rates for the switch can be assumed to be e.g. 50 Hz.

Figure 5 is a schematic representation of one embodiment. A structured
15 noise of the a.c. voltage perturbation signal was calculated by a computer and sent to the memory of the multifunctional generator (54) (Analogic[®] 2030A). This device generates the perturbation signal and feeds it into the patch clamp amplifier (56) (HEKA[®] EPC8).

When digital data records are used for the perturbation signal, the
20 transitions between the discrete voltage steps should be small and smoothed because this reduces the level of background noise of the perturbation signal. In order to have small steps between two consecutive values of the perturbation signal, the sampling rate at which the data record is output by the function generator should be greater by a factor of about ten than the largest frequency of
25 interest in the impedance spectra.

To smooth the discrete steps, the perturbation signal can be filtered with a lowpass filter, with the corner frequency of the filter greater by a factor of about ten above the highest frequency of interest in the impedance spectra. The patch clamp amplifier (56) transmits the a.c. voltage perturbation signal via an external
30 preamplifier (58) to the sample (60) under test. This preamplification unit simultaneously measures the actual a.c. voltage applied to the sample and the

current response of the sample. The current signal is filtered, amplified and undergoes current to voltage conversion. Both time signals $U(t)$ and $I(t)$ can be monitored as voltage signals at the corresponding outputs of the patch clamp amplifier (56). Both signals are acquired by two channels of the A/D converter board (National Instruments Lab-NB) in a measuring computer (Apple Macintosh IIfx) and saved in data records on the computer data storage media.

The software necessary to operate the setup includes two programs. The first program performs the data acquisition on the measuring computer with the A/D converter board. It includes the data analysis software Igor Pro[®] (WaveMetrics) with an expansion package for data acquisition (NIDAQ Tools). The second program performs the signal processing and data analysis of the measured data records of $U(t)$ and $I(t)$. It is a custom-written C++ program for Macintosh and Windows operated PCs. The implemented algorithm of the sliding short time Fourier transform is based on a modified Cooley-Tukey FFT algorithm.

To fit the equivalent circuits to the impedance spectra, a modified minimizing algorithm was derived from the method of Powell in multidimensions. For the above-specified application, the logarithms of the real part and the negative imaginary part of the impedance spectra (complex coordinates) were used for the data fitting by the minimization procedure. See W.H. Press, S.A. Teukolsky, W.T. Vetterling *et al.* Numerical Recipes in C (Cambridge University Press, New York, 1992).

The performance characteristics of the described embodiment were quantified in simulations and test measurements. For the simulations, the corresponding current response signals of an ideal system were calculated by the computer for the structured noise perturbation signals, and the generated signals $U(t)$ and $I(t)$ were evaluated using the signal processing and data analysis procedure of highly time resolved impedance spectroscopy. Figure 6 is a table that shows examples of parameters for the structured noise signal (66) and data processing (68) in the "Simulations" column. The simulations demonstrate that a membrane/ion channel system with characteristic quantities $R_1 = 100 \text{ k}\Omega$, R_2 switching between distinct values in a range of $0.8\text{-}20 \text{ G}\Omega$ and $C = 6 \text{ pF}$ can be

measured correctly by using the logarithms of the complex coordinates in a minimization procedure even in a narrow frequency band of 0.3-20 kHz with only six individual frequencies. In general, for the analysis of impedance spectra of membrane ion channel systems a frequency band of 100 Hz to 100kHz may be used.

The equivalent circuit of the membrane/ion channel system is provided by Figure 4, where the combination of R_{2a} and R_{2b} is considered as R_2 .

In Figure 7 the time course (72) of the switchable parallel resistor R_2 is shown as it was assumed for the simulation (74) (continuous line) and as determined by highly time resolved impedance spectroscopy (76) (circle). Figure 8 shows one jump (82) in R_2 enlarged from Figure 7. The different curves shown result from using different window functions $g(t)$ in the short time Fourier transform. Window functions of the following characteristics were used: Hanning 1.0 (Cos.) (84), Kaiser-Bessel with $\alpha=2.0$ (KB2) (86), and Kaiser-Bessel with $\alpha=3.5$ (KB3) (88). The analysis of the time course reveals, that in the absence of any signal corruption, the time course of the system-characterizing quantities determined by the short time Fourier transform corresponds to the convolution of the real (ideal) time course of this quantity with the window function used. The time resolution attained was $\Delta\tau = 0.67$ ms, and the rise time τ_r was between 2.0 and 3.1 ms depending on the window function.

For the test measurements, the circuit in Figure 4 was assembled by using electronic components. Such a circuit forms a model sample, which mimics the behavior of individual ion channels in supported lipid membranes. These model samples were measured by highly time resolved impedance spectroscopy.

In a first test measurement, a model was used with the values of $R_{2a, 2b} = 680$ K Ω and $C = 1$ nF (no additional element for R_1), and the switch was switched at a frequency of 50 Hz. Figure 6 shows the parameters of the structured noise signal and the data evaluation in the column, "fast model." In Figure 9 the time courses of R_1 (92), R_2 (94) and C (96) are shown as determined with highly time resolved impedance spectroscopy, as well as an ideal or absolute time course of R_2 (98).

Deviations from the absolute values of up to 20% result from the insufficiently compensated filter effects of the setup. The step-like changes of R_2 are reproduced well. The attained time resolution was 1.1.ms, and the rise time was 8 ms. In Figure 10 (a) and (b) the real and negative imaginary part
5 respectively of the underlying impedance spectra (112) and (104) for two points in the time courses of Figure 9 are shown. Not each of the contributing frequencies of the structured noise signal was used for the evaluation but just the limited range of 0.4-4 kHz.

In a second test measurement, a model was used with the values of $R_{2a, 2b}$
10 $= 1 \text{ G}\Omega$ and $C = 3 \text{ pF}$ (no additional element for R_1), and the switch was switched manually at irregular intervals. Figure 6 shows the parameters of the structured noise signal and the data evaluation in the column "Gigaohm Model." In Figure 11 the time courses of R_1 (112), R_2 (114) and C (116) as determined by highly time resolved impedance spectroscopy are shown. Again, deviations from
15 the absolute values of up to 20% result from the insufficiently compensated filter effects of the setup. The step-like changes of R_2 are clearly resolved also at these high impedances. The attained time resolution was 4.4 ms. In Figure 12 (a) and (b) the real and negative imaginary parts respectively of the underlying impedance spectrum of one point (122) in the time courses in Figure 11 is shown. Just five
20 contributing frequencies in the impedance spectrum were sufficient to determine three independent, partially dynamic variables from the impedance spectra. This proves the significantly higher information content of measurements using highly time resolved impedance spectroscopy even in a very limited frequency band in comparison to measuring resistance at only one frequency.

Figure 13 is a block diagram illustrating one embodiment of the highly time resolved impedance spectroscopy. As illustrated in Figure 13, the basic setup for highly time resolved impedance spectroscopy requires just a few components. A main processor (132) unit controls signal generation and data acquisition on two channels. The data for the structured noise signal are generated by the processor
25 unit according to a stored algorithm, stored in a memory device (134) and the voltage signal is applied to an output after a D to A converter (136). The
30

measured voltage signal $U(t)$ undergoes A to D conversion, at converter (138), at an input channel and is transferred to the memory. At the second input channel, the current signal $I(t)$ is received by a signal conditioner (142) and undergoes current to voltage conversion at an A to D converter (144). The output of the
5 converter (144) is transferred to memory. The measured data of the voltage and current signal are processed and analyzed with a routine stored in a memory device (146), and the results are saved on the data storage media (140). In another embodiment, the two memory devices (134) and (136) are the same memory device

10 As described above, the use of the highly time resolved impedance spectroscopy has many advantages over conventional impedance spectroscopy. Some of the advantages include: substantial improvement in the time resolution of impedance spectroscopy; time resolution down to a fraction of each individual frequency in the impedance spectrum; continuous measurement with fast response
15 times; real-time measurements; optimization of the measuring procedure by adapting the perturbation signal and the data processing and analysis to the investigated system; repeated analysis of the measured data records adapted to the focus of the evaluation; highly flexible technique; investigation of dynamic processes that previously could not be measured with impedance spectroscopy
20 such as opening and closing individual ion channels in natural or artificial, free or supported membranes; and highly favorable signal to noise ratio.

In another aspect of the invention, the problem faced by researchers using impedance spectroscopy instrumentation when multiplexed analysis is performed is addressed. Impedance data prior to the making of this invention was displayed
25 graphically as either a numerical value or a point on an x-y graph, or as a bar graph, which was cumbersome to analyze. The invention provides for displaying the data as a color from a color scale in a two-dimensional layout that corresponds to the relative position of each channel of data from the multiplexed assay within the test matrix. See Figure 14 where membrane conductance is represented in the
30 upper panels as a graphical user interface (GUI) output, and membrane capacitance is represented in the lower panels as a GUI. Note that the arrangement of each colored box corresponds to the electrical readout at each

electrode within the 6X6 matrix of 6 channels with 6 electrodes within each channel. If different colors are used for different types of data, as shown in Figure 14, then such different data can be combined in sub square formats, e.g., half green-to-yellow/half orange-to-brown triangles forming together a square where
5 the green/brown box represents a fully annealed or sealed membrane or lipid bilayer and positive response and a yellow/orange box indicates dysfunctional membrane or lipid bilayer with a negative result.

The foregoing description details certain embodiments of the invention. It will be appreciated, however, that no matter how detailed the foregoing appears,
10 the invention may be embodied in other specific forms without departing from its spirit or essential characteristics. The described embodiments are to be considered in all aspects only as illustrative and not restrictive and the scope of the invention is, therefore, indicated by the appended claims rather than by the foregoing description. All changes which come within the meaning and range of
15 equivalency of the claims are to be embraced within their scope.

We Claim:

1. A method of data processing, comprising:
receiving impedance spectra data from a plurality of measurement
5 electrodes within a test matrix; and
displaying the impedance spectra data in a two-dimensional array of a
display, wherein an element of the two-dimensional array relates to a relative
position of a corresponding measurement electrode within the test matrix, and
wherein the impedance spectra data is displayed using a color that indicates a
10 value of the impedance spectra data of the corresponding measurement electrode
within the test matrix.
2. A method as defined in Claim 1, wherein the test matrix comprises six
channels with six measurement electrodes within each channel.
15
3. A method as defined in Claim 2, wherein displaying the impedance spectra
data in a two dimensional array comprises displaying the impedance data in a six
by six array.
- 20 4. A method as defined in Claim 1, wherein the impedance spectra data is a
conductance.
5. A method as defined in Claim 1, wherein the impedance spectra data is a
capacitance.
25
6. A method as defined in Claim 1, wherein the impedance spectra data is
obtained from measurements on ion channels in supported lipid membranes.
7. A method as defined in Claim 1, wherein different colors are used to
30 indicate a data type.
8. A method as defined in Claim 7, wherein the data type is a conductance.

9. A method as defined in Claim 7, wherein the data type is a capacitance.
10. A method as defined in Claim 1, wherein the elements of the two-dimensional array comprise sub-elements.
11. A method as defined in Claim 10, wherein each sub-element indicates a different data type at a corresponding measurement electrode within the test matrix.
12. A method as defined in Claim 11, wherein the data type is a conductance.
13. A method as defined in Claim 11, wherein the data type is a capacitance.
14. A method as defined in Claim 10, wherein there are two sub-elements in an element of the two-dimensional array.
15. A method as defined in Claim 14, wherein the sub-elements are triangles that together form a square.
16. An apparatus that measures highly time resolved impedance spectra, comprising:
- a processor that receives impedance spectra data from a plurality of measurement electrodes within a test matrix and produces output data for display;
- and
- a display that shows the output data as a two-dimensional array representing a measured impedance spectra from the measuring electrodes in the test matrix, wherein an element of the two-dimensional array relates to a relative position of a corresponding measurement electrode within the test matrix, and wherein the impedance spectra data is displayed using a color that indicates a value of the impedance spectra data of the corresponding measurement electrode within the test matrix.

17. An apparatus as defined in Claim 16, wherein the test matrix comprises six channels with six measurement electrodes within each channel.
- 5 18. An apparatus as defined in Claim 17, wherein displaying the impedance spectra data in a two dimensional array comprises displaying the impedance data in a six by six array.
- 10 19. An apparatus as defined in Claim 16, wherein the impedance spectra data is a conductance.
20. An apparatus as defined in Claim 16, wherein the impedance spectra data is a capacitance.
- 15 21. An apparatus as defined in Claim 16, wherein the impedance spectra data is obtained from measurements on ion channels in supported lipid membranes.
22. An apparatus as defined in Claim 16, wherein different colors are used to indicate a data type.
- 20 23. An apparatus as defined in Claim 22, wherein the data type is a conductance.
24. An apparatus as defined in Claim 23, wherein the data type is a
- 25 capacitance.
25. An apparatus as defined in Claim 16, wherein the elements of the two-dimensional array comprises sub-elements.
- 30 26. An apparatus as defined in Claim 25, wherein each sub-element indicates a data type at a corresponding measurement electrode within the test matrix.

27. An apparatus as defined in Claim 26, wherein the data type is a conductance.
28. An apparatus as defined in Claim 26, wherein the data type is a
5 capacitance.
29. An apparatus as defined in Claim 25, wherein the display element includes two sub-elements.
- 10 30. An apparatus as defined in Claim 29, wherein the two sub-elements are triangles that together form a square.

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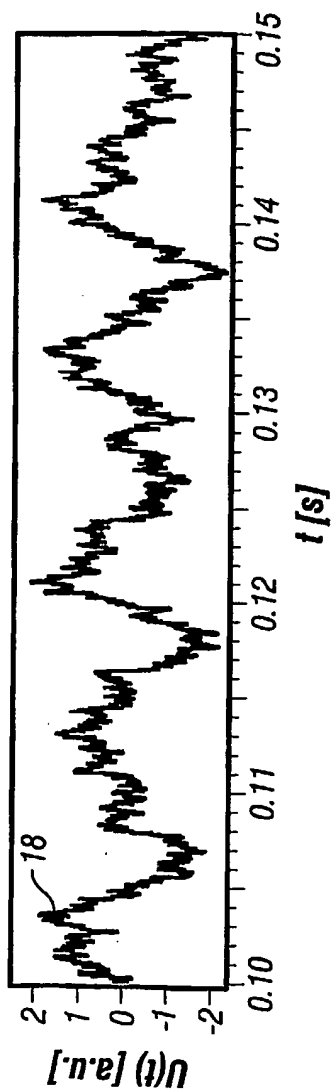


FIG. 1

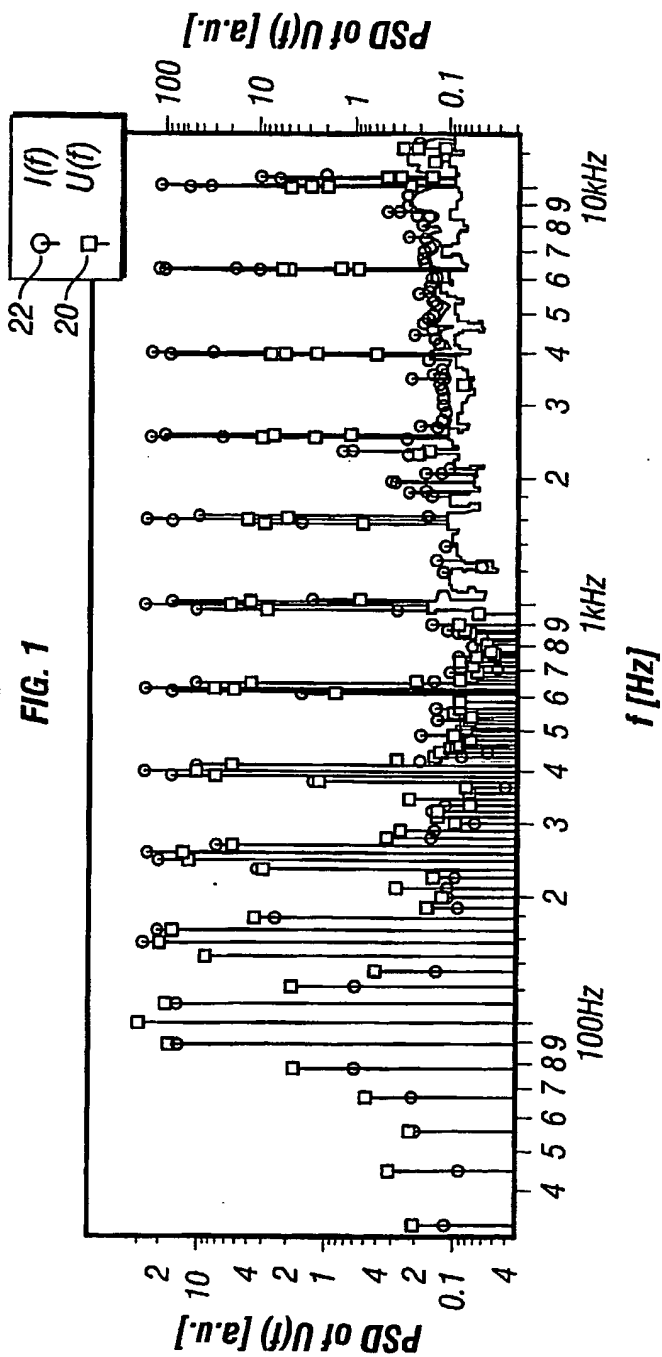


FIG. 2

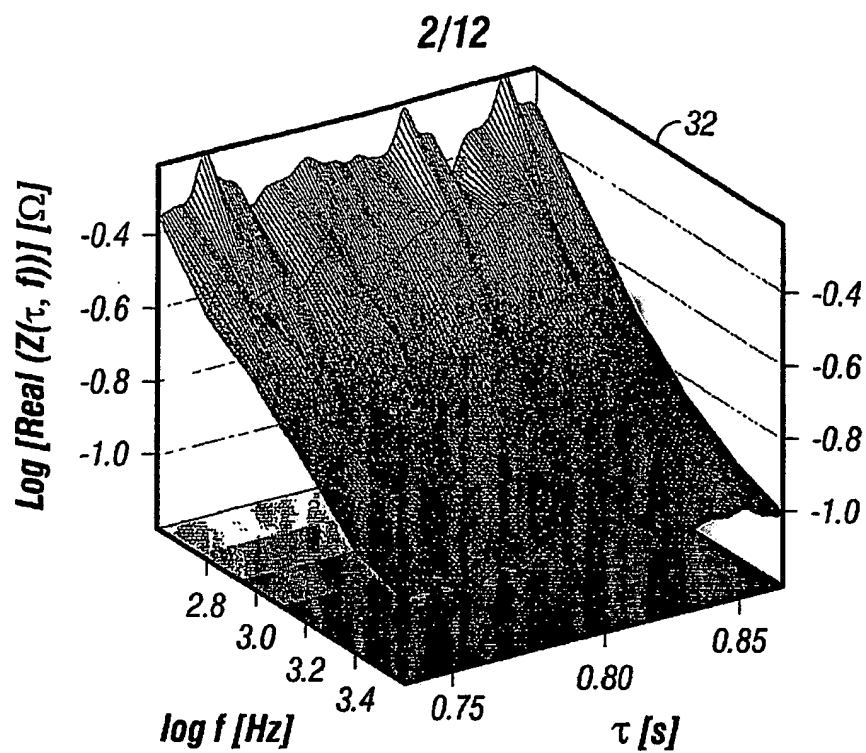


FIG. 3A

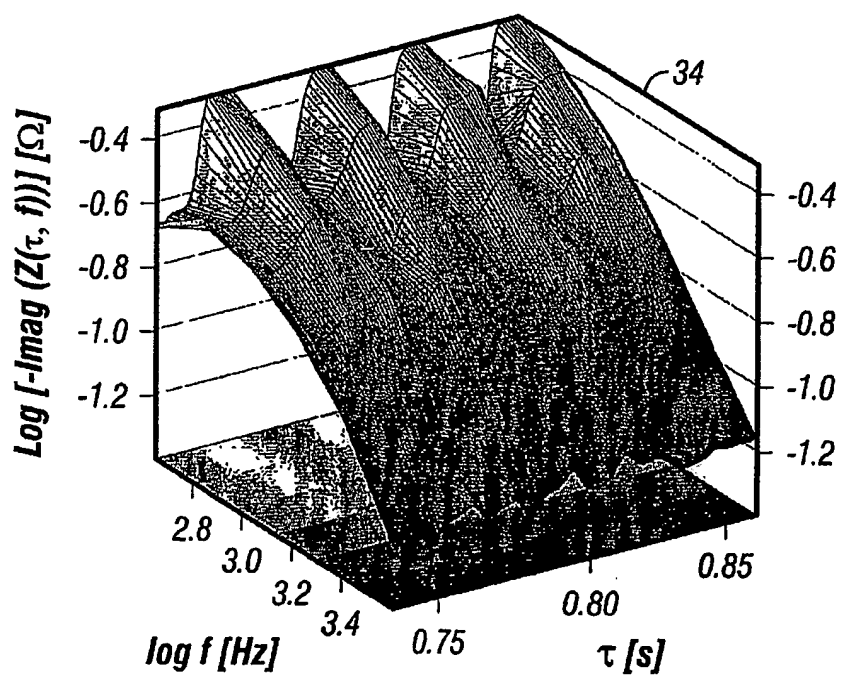


FIG. 3B

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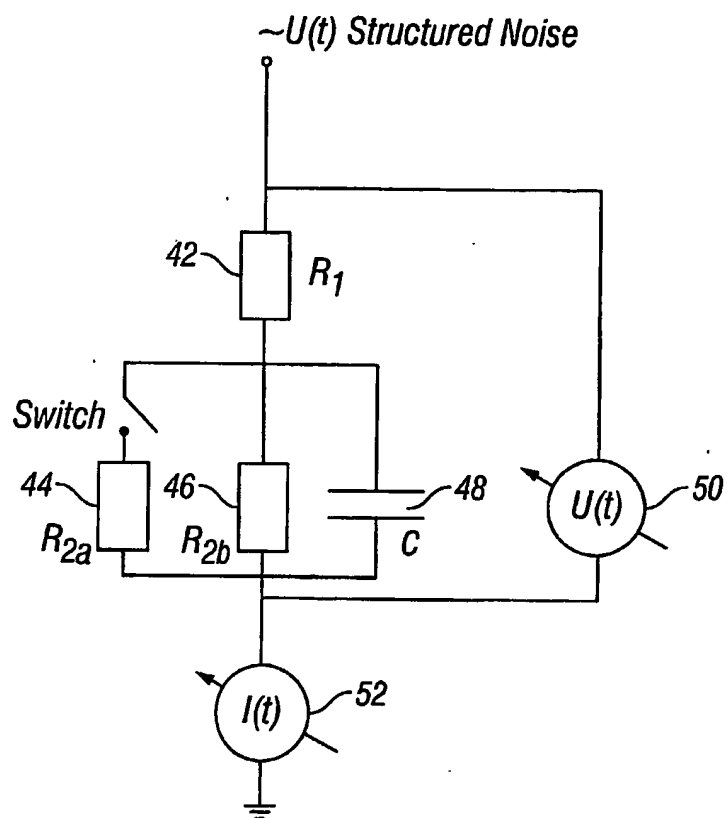


FIG. 4

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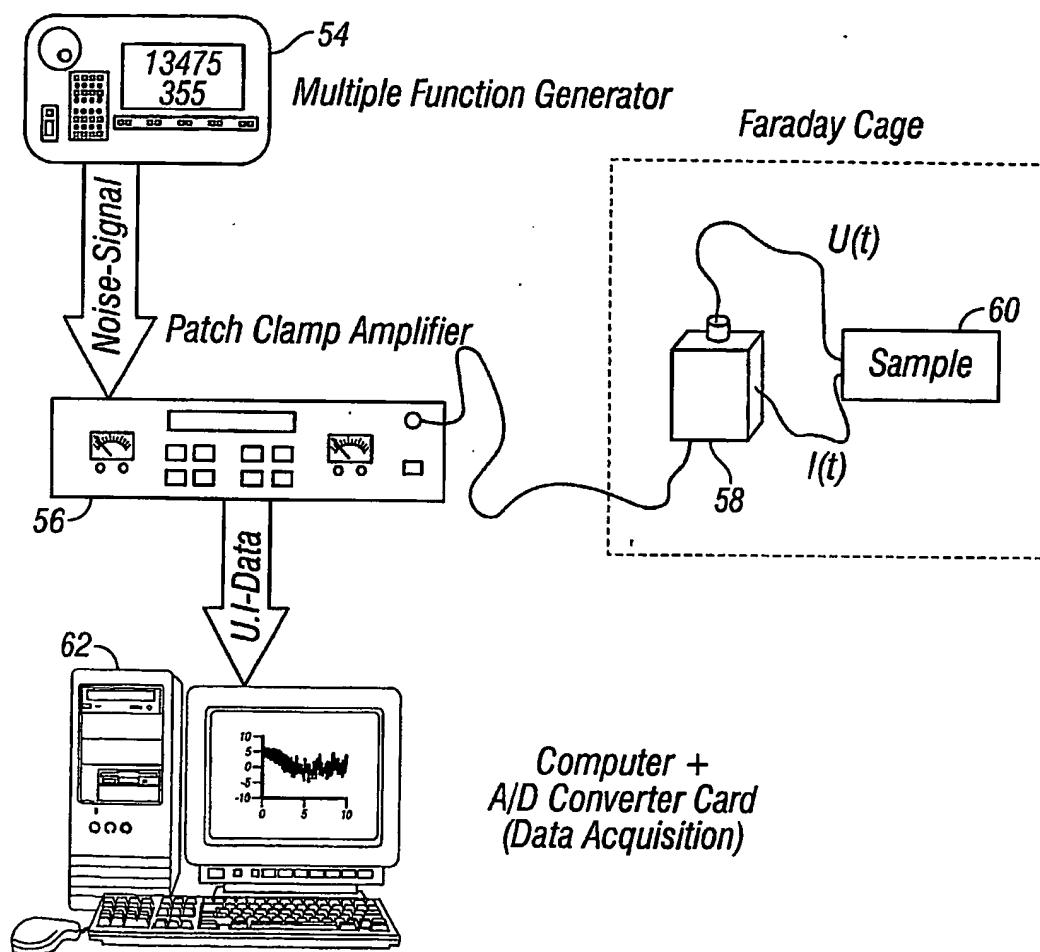


FIG. 5

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Simulation		Fast Model		Gigaohm Model		
Structured Noise Signal						
66	$U_{0, tot} (V)$	Any Number	$U_{0, tot} (V)$	0.05	$U_{0, tot} (V)$	0.1
	n	6	n	11	n	5
Contained Frequencies						
F_i (Hz)	$U_{0,i}/U_{0,1}$	F_i (Hz)	$U_{0,i}/U_{0,1}$	F_i (Hz)	$U_{0,i}/U_{0,1}$	
371.1	1	100	1	100	1	
1113	0.334	158.5	0.631	239.9	0.646	
1855	0.2	251.2	0.398	575.4	0.417	
4082	0.091	398.1	0.251	1380	0.270	
8906	0.417	631.0	0.158	3311	0.174	
19667	0.019	1000	0.1			
		1585	0.063			
		2512	0.040			
		3981	0.025			
		6310	0.016			
		10000	0.01			
Data Analysis						
68	ΔN	32	ΔN	50	ΔN	200
	N_w	256	N_w	1024	N_w	2048
	Window	(*)	Window	KB 3.5	Window	KB 2.0

FIG. 6

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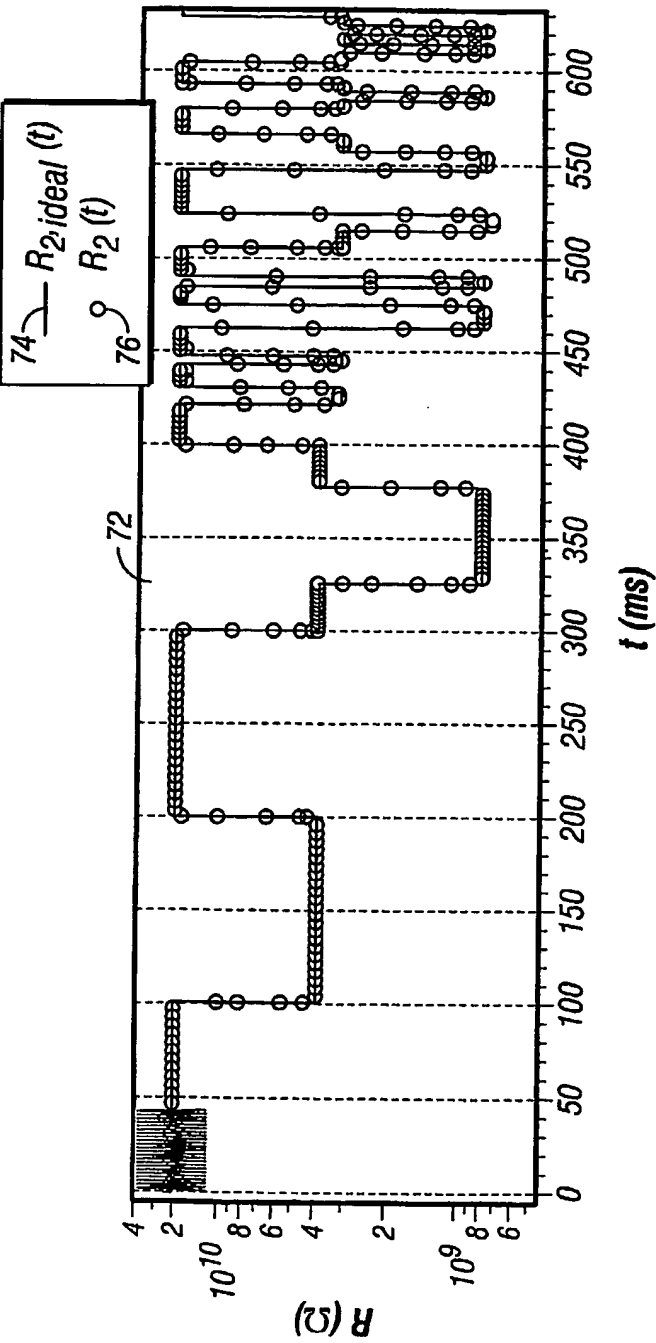


FIG. 7

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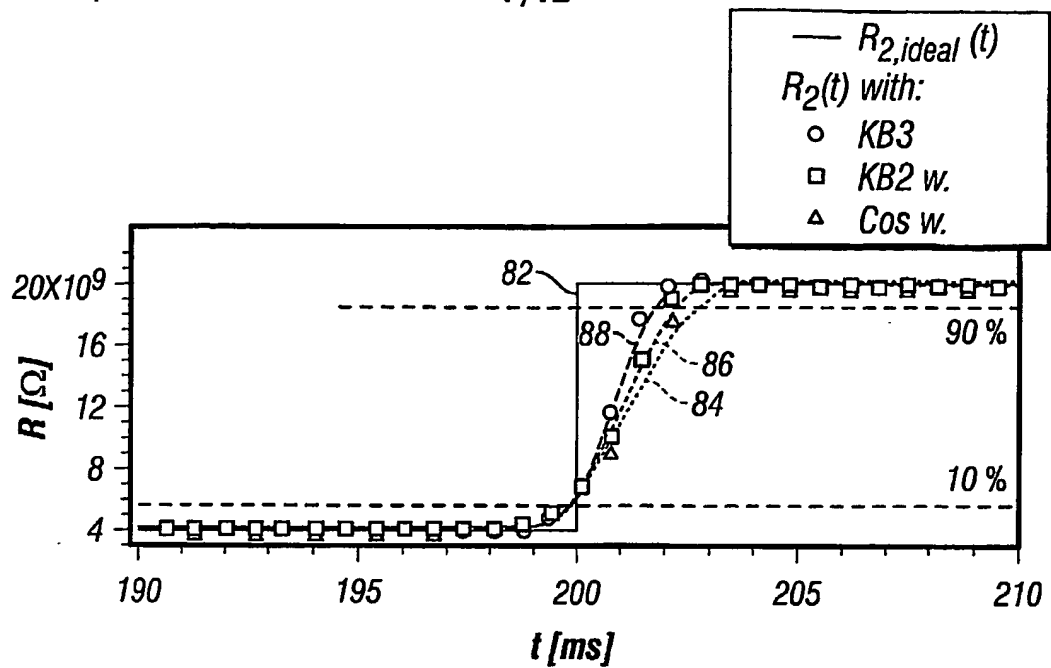


FIG. 8

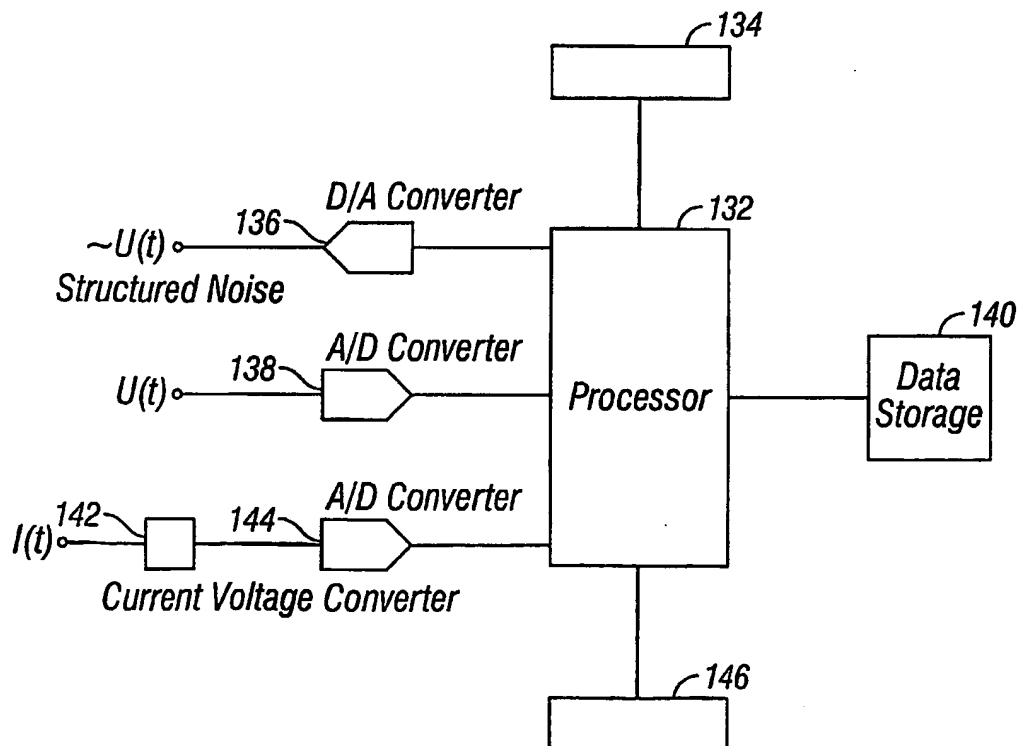


FIG. 13

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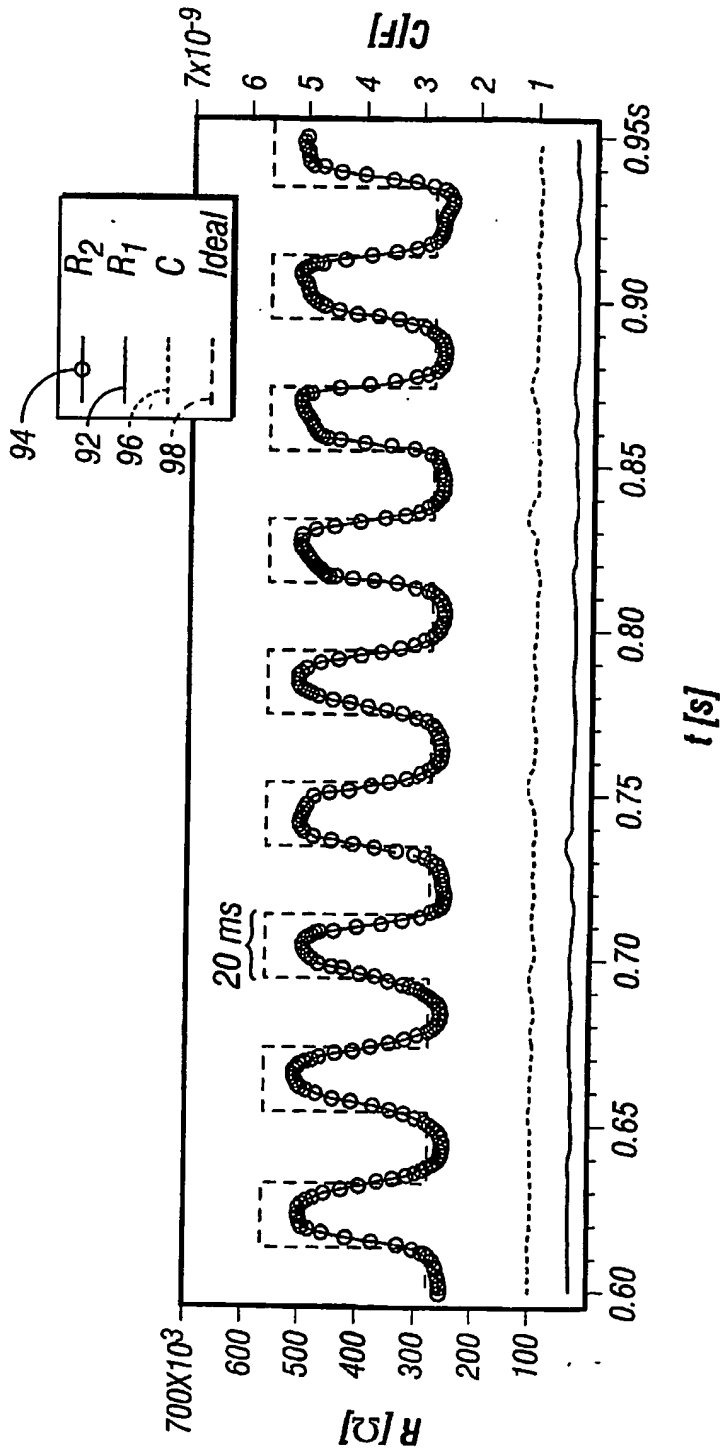


FIG. 9

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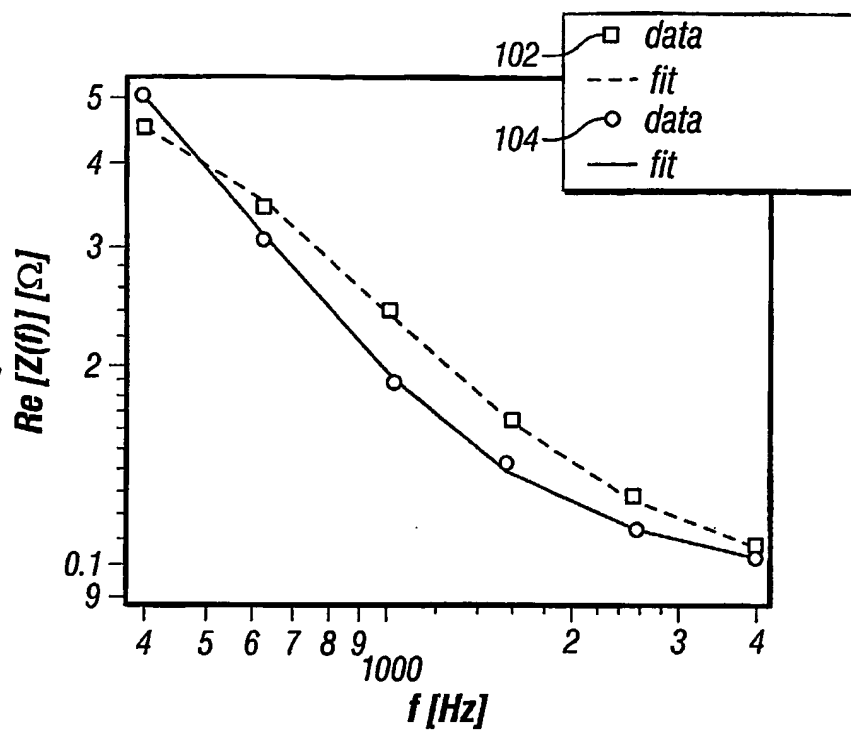


FIG. 10A

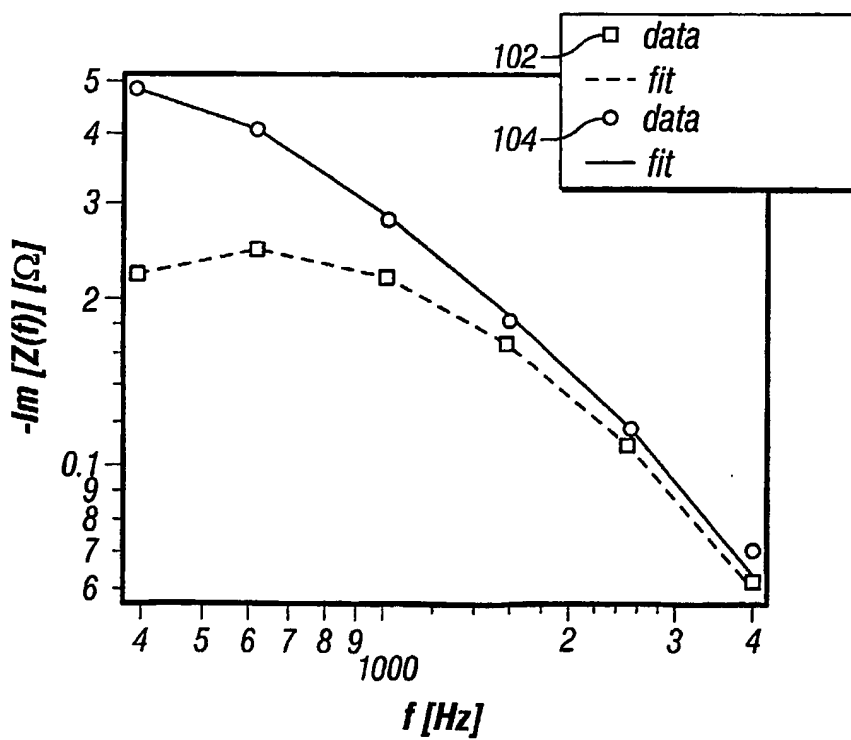


FIG. 10B

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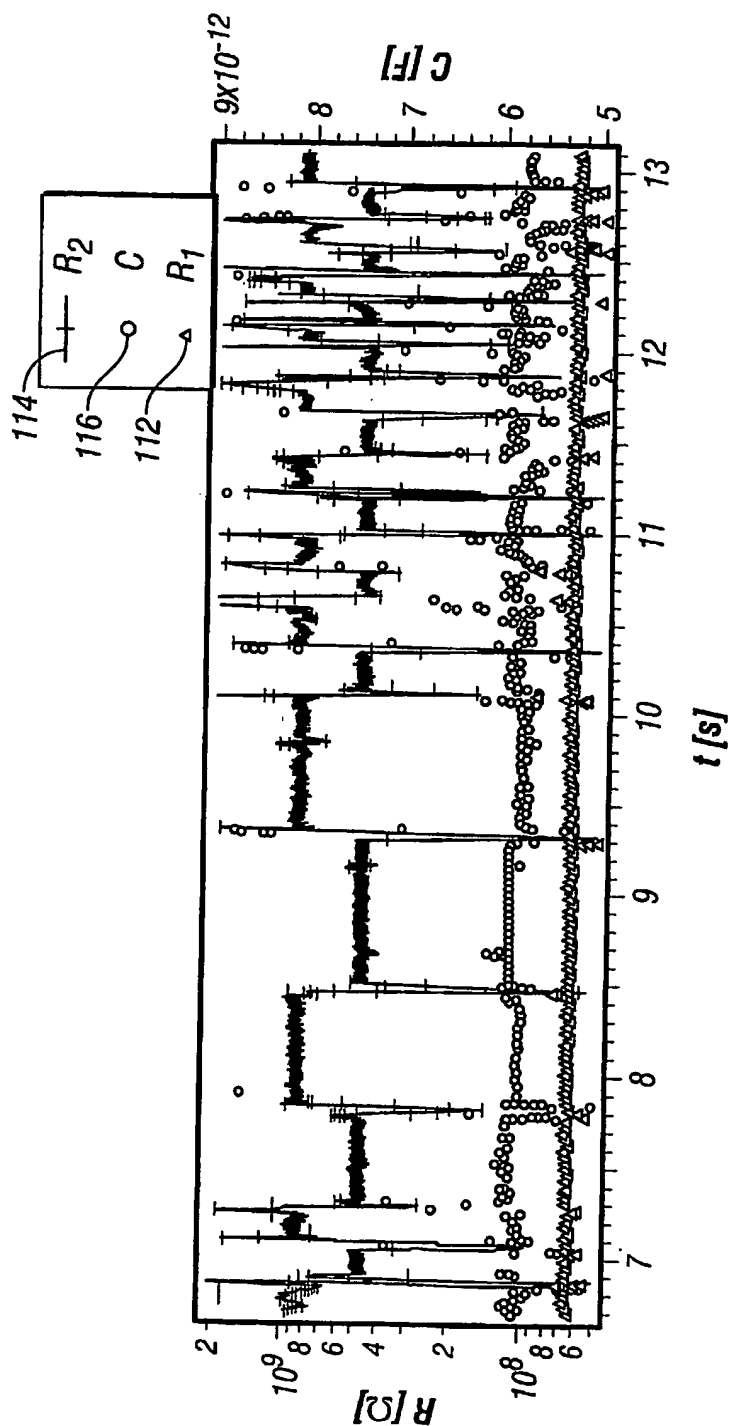


FIG. 11

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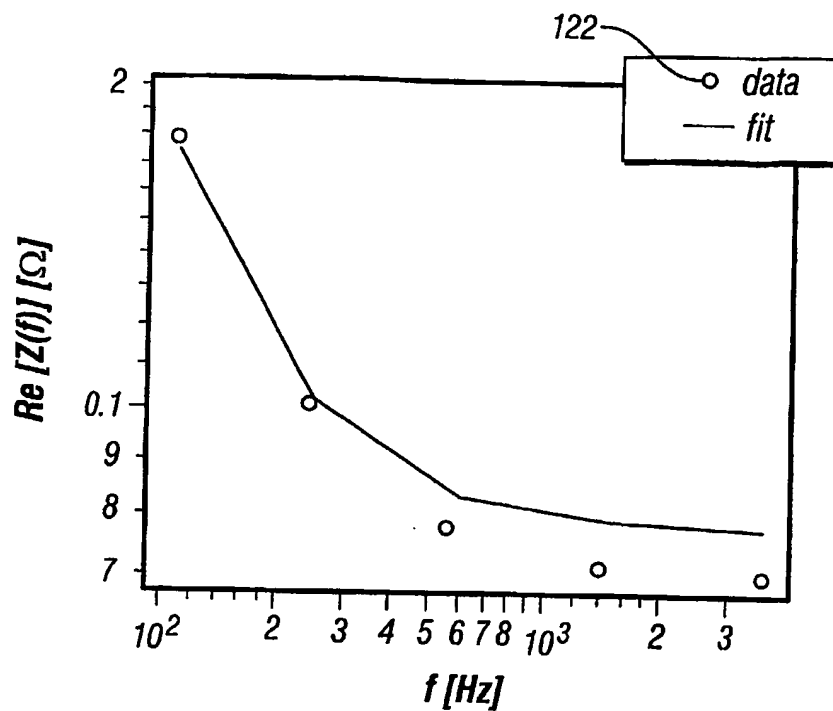


FIG. 12A

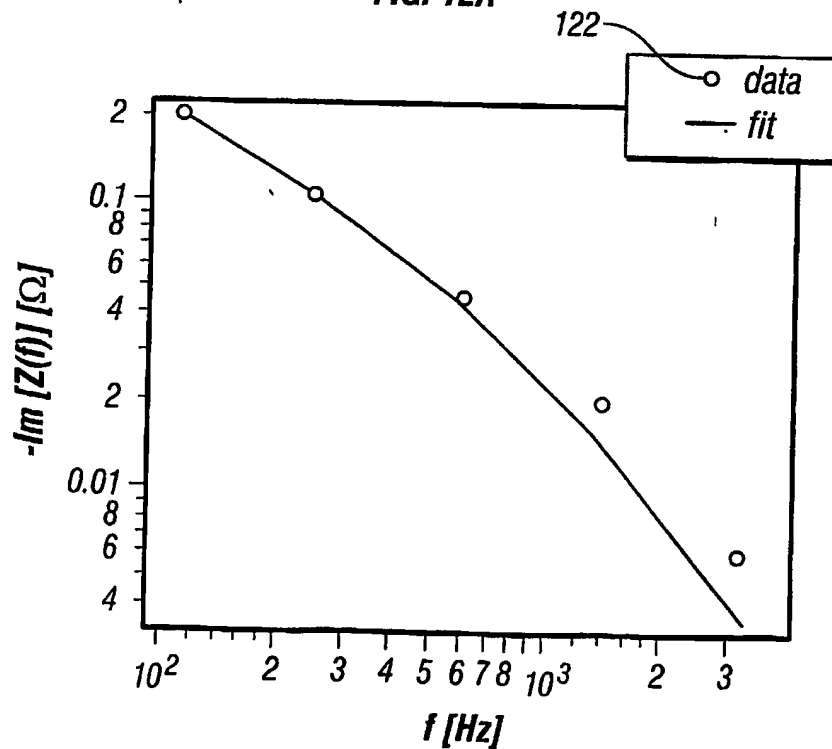


FIG. 12B

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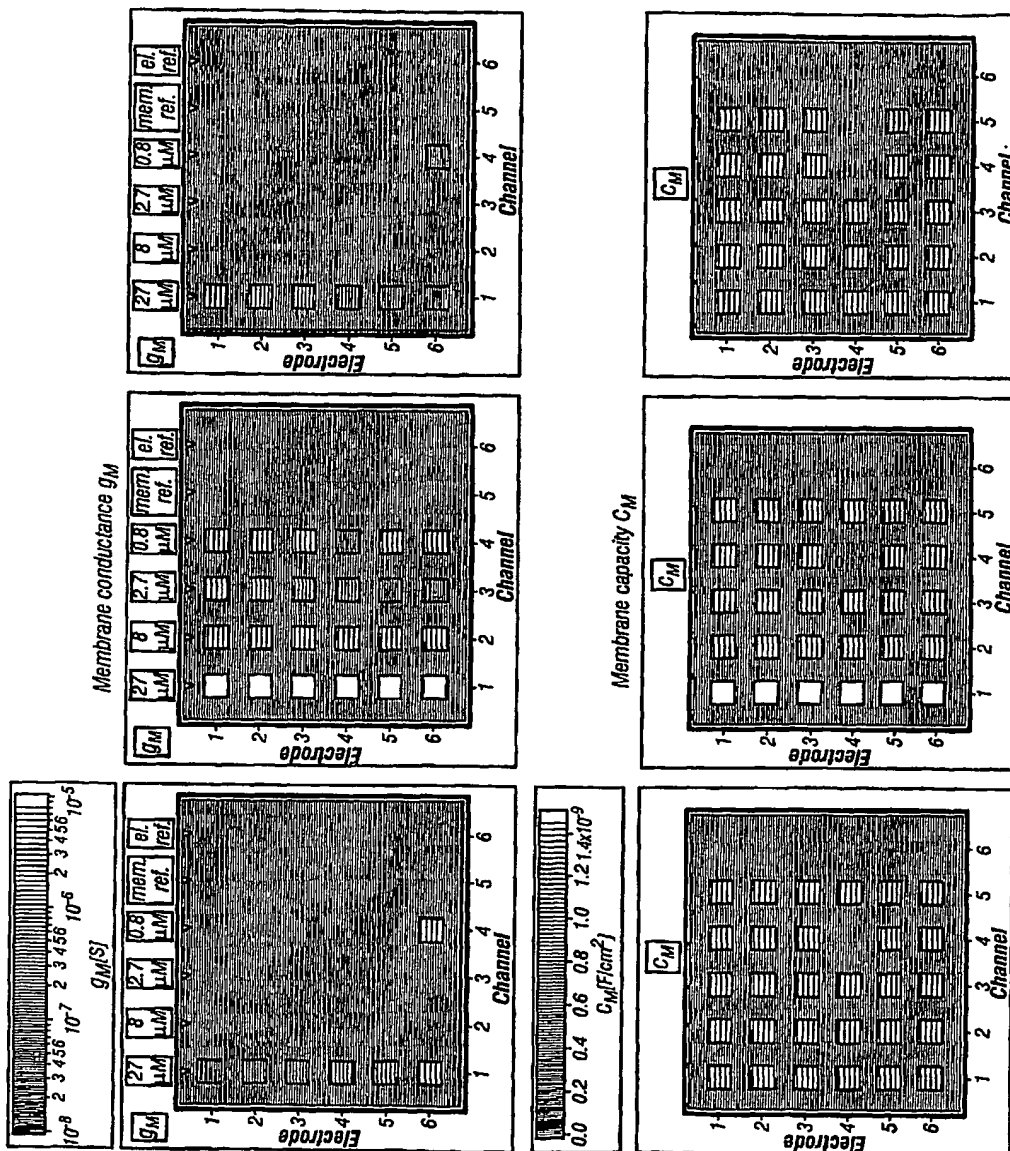


FIG. 14

INTERNATIONAL SEARCH REPORT

International Application No

PCT/US 03/05810

A. CLASSIFICATION OF SUBJECT MATTER IPC 7 G01N27/02 G01N33/543		
According to International Patent Classification (IPC) or to both national classification and IPC		
B. FIELDS SEARCHED Minimum documentation searched (classification system followed by classification symbols) IPC 7 G01N		
Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched		
Electronic data base consulted during the international search (name of data base and, where practical, search terms used) WPI Data, EPO-Internal		
C. DOCUMENTS CONSIDERED TO BE RELEVANT		
Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	DE 100 18 745 A (SACKMANN ERICH ;WIEGAND GERALD (DE)) 19 April 2001 (2001-04-19) the whole document ---	1-29
X	WO 01 27605 A (SACKMANN ERICH ;WIEGAND GERALD (US)) 19 April 2001 (2001-04-19) cited in the application claims 1-35 ---	1-29
X	US 5 981 268 A (BORKHOLDER DAVID A ET AL) 9 November 1999 (1999-11-09) abstract; figures 3,4,7B,8B, column 17, line 44 -column 18, line 14 --- -/--	1-29
<input checked="" type="checkbox"/> Further documents are listed in the continuation of box C. <input checked="" type="checkbox"/> Patent family members are listed in annex.		
* Special categories of cited documents : *A* document defining the general state of the art which is not considered to be of particular relevance *E* earlier document but published on or after the international filing date *L* document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) *O* document referring to an oral disclosure, use, exhibition or other means *P* document published prior to the international filing date but later than the priority date claimed *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art. *&* document member of the same patent family		
Date of the actual completion of the international search 6 August 2003		Date of mailing of the international search report 14/08/2003
Name and mailing address of the ISA European Patent Office, P.B. 5818 Patentlaan 2 NL - 2280 HV Rijswijk Tel. (+31-70) 340-2040. Tx. 31 651 epo nl. Fax: (+31-70) 340-3016		Authorized officer Klein, M-O

INTERNATIONAL SEARCH REPORT

International Application No

PCT/US 03/05810

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT		
Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	<p>SINNER A ET AL: "The electrical characterization of supported phospholipid bilayers using titanium/titanium oxide microelectrodes"</p> <p>PREPARATION AND CHARACTERIZATION, ELSEVIER SEQUOIA, NL,</p> <p>vol. 327-329, 31 August 1998 (1998-08-31), pages 758-761, XP004355820</p> <p>ISSN: 0040-6090</p> <p>the whole document</p> <p>---</p>	1-29
A	<p>SACKMANN E E ET AL: "Supported membranes on soft polymer cushions: fabrication, characterization and applications"</p> <p>TRENDS IN BIOTECHNOLOGY, ELSEVIER, AMSTERDAM, NL,</p> <p>vol. 18, no. 2, February 2000 (2000-02), pages 58-64, XP004187251</p> <p>ISSN: 0167-7799</p> <p>the whole document</p> <p>---</p>	1-29
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A	<p>US 6 291 155 B1 (CORNELL BRUCE ET AL) 18 September 2001 (2001-09-18)</p> <p>the whole document</p> <p>---</p>	1-29
A	<p>POPKIROV G S: "Fast time-resolved electrochemical impedance spectroscopy for investigations under nonstationary conditions"</p> <p>ELECTROCHIMICA ACTA, ELSEVIER SCIENCE PUBLISHERS, BARKING, GB,</p> <p>vol. 41, no. 7, 6 May 1996 (1996-05-06), pages 1023-1027, XP004019433</p> <p>ISSN: 0013-4686</p> <p>the whole document</p> <p>-----</p>	1-29

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No

PCT/US 03/05810

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